Modeling the power-reliability tradeoff in on-chip networks

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12. SYMPOSIUM MARITIME ELEKTROTECHNIK, ELEKTRONIK UND INFORMATIONSTECHNIK

Outline

- Introduction
  - System design
  - Technology issues
- Approach
  - Analytical models
  - Simulation
- Results
- Summary

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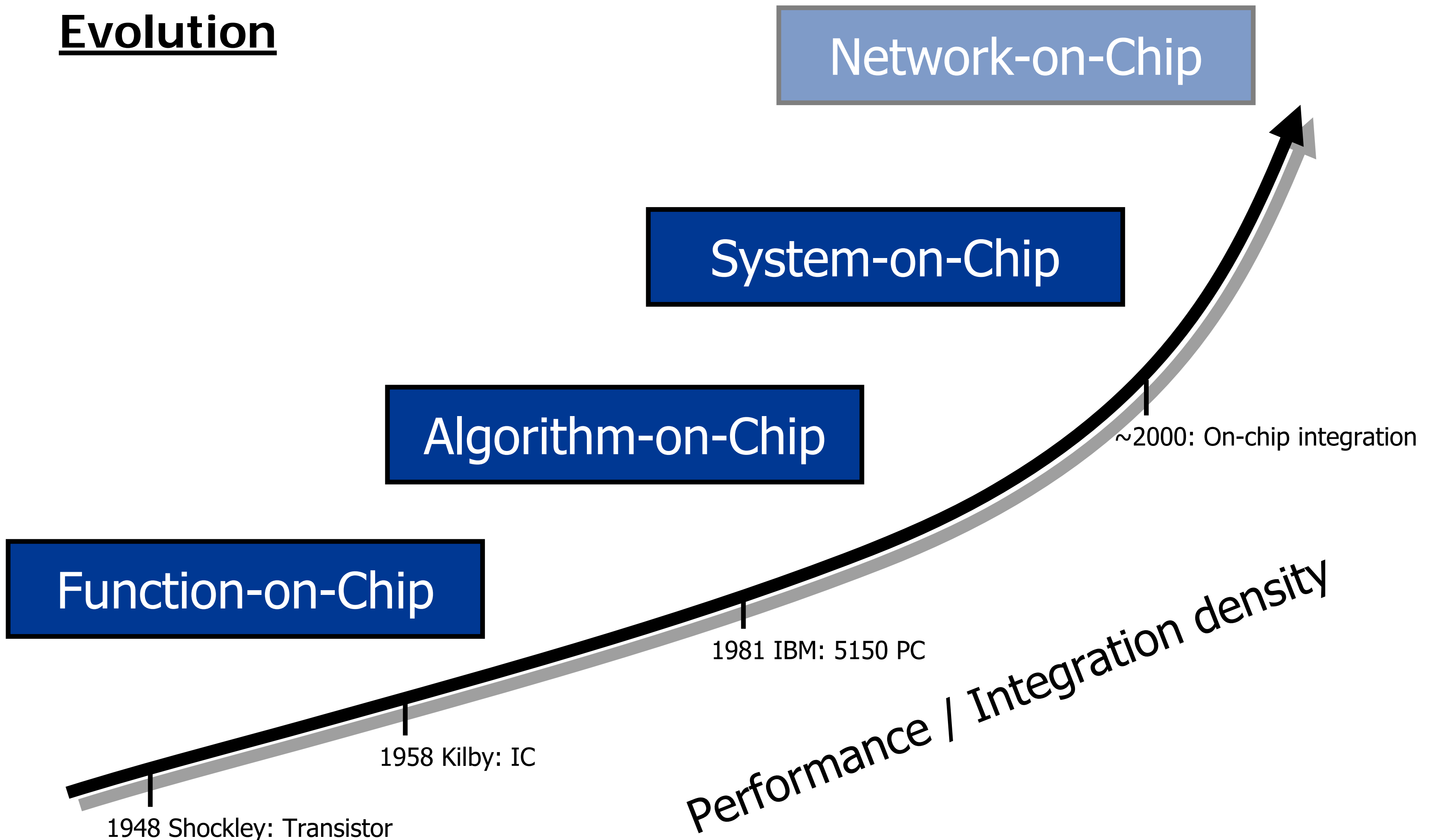
System design

Evolution

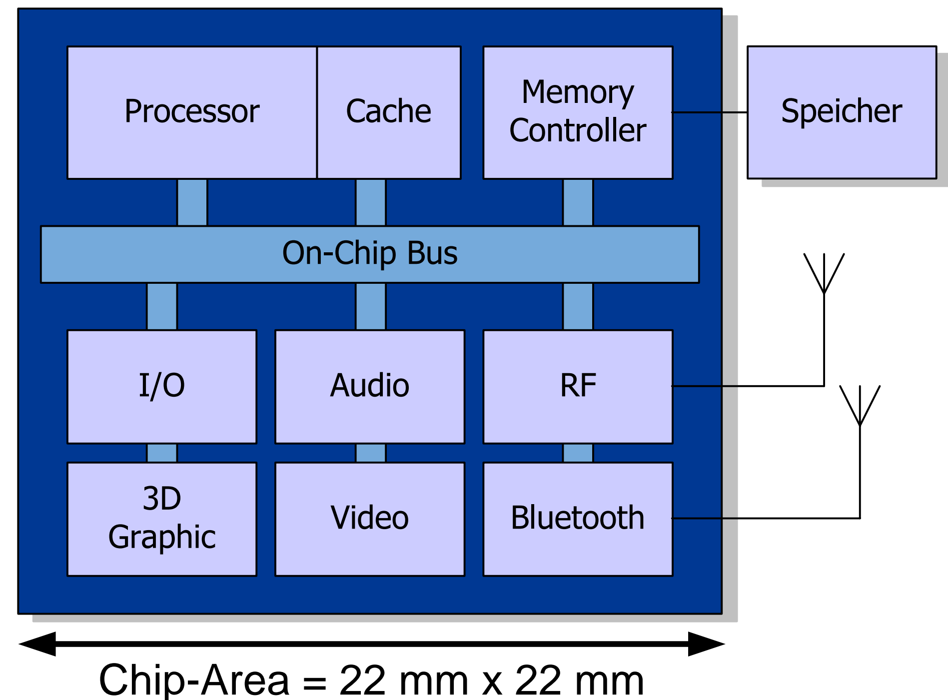


System design

Bus-based system design

➔ Shared communication medium

- Connected problems:
  - Memory-Bottleneck
  - Design-Productivity-Gap
  - Synchronous design

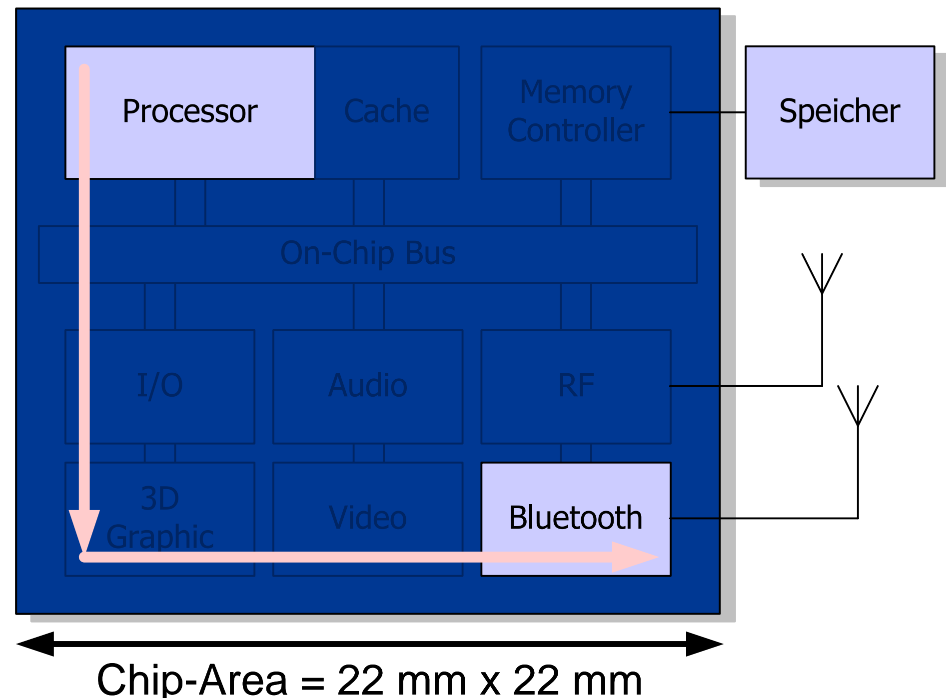


System design

Bus-based system design

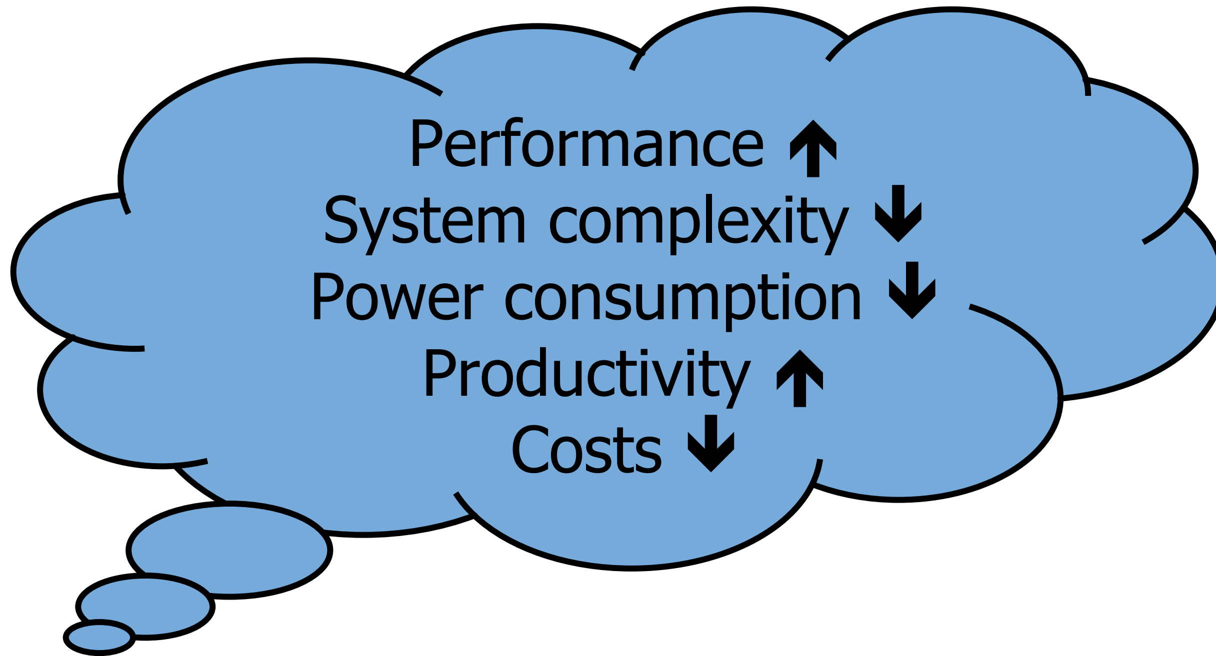
➔ Shared communication medium

- Connected problems:
  - Memory-Bottleneck
  - Design-Productivity-Gap
  - Synchronous design
- Worsening the situation:
  - Chip-Size
  - Interconnects
  - Integration density
  - Parameter variability
  - ... and many more



System design

Wish list



[Intel]

" … multi-core processors are another […] 10x factor in terms of performance … "

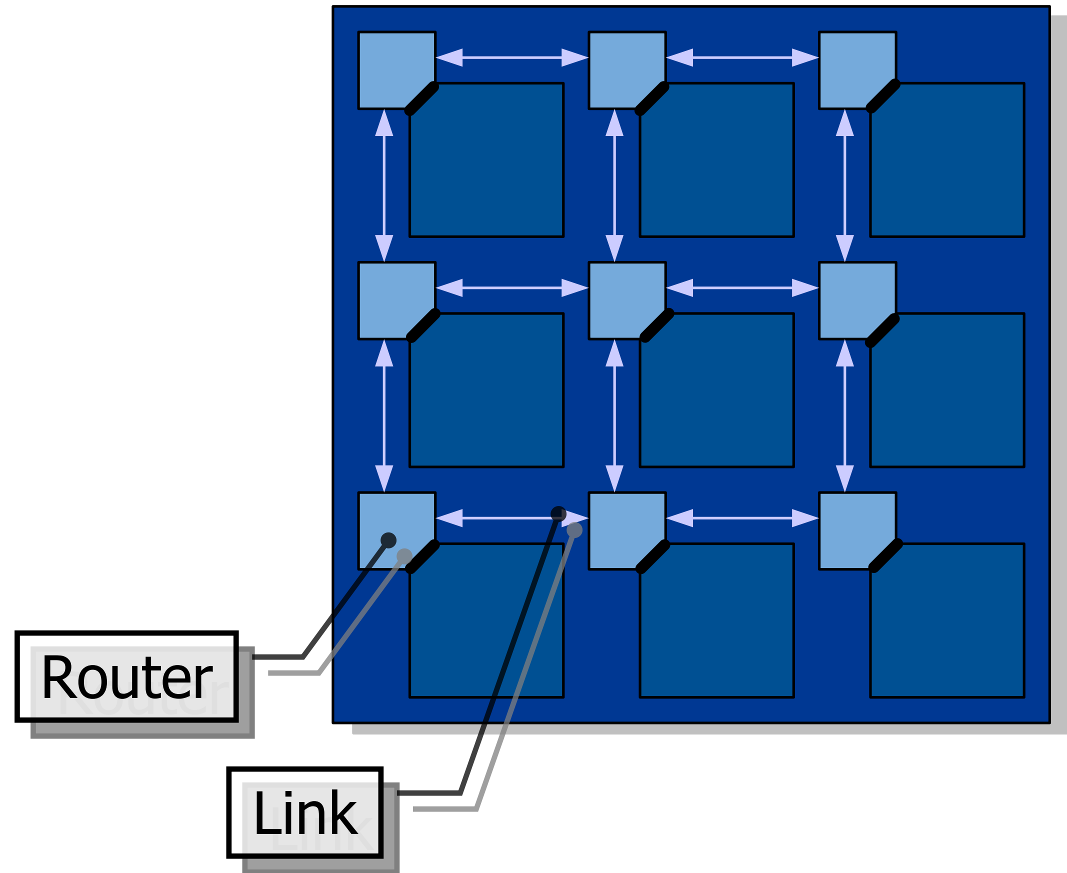
Paul Otellini, Intel President
IDF, September 2004

System design

Network-on-Chip

Promising properties:

- Parallelism
- Modularity



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System design

Network-on-Chip

Promising properties:

- Parallelism
- Modularity

Level of abstraction:

Modules
Logic-Gates
Transistors
Polygons

3D
Memory
I/O
Video
CPU
RF
Audio
Crypto
Bluetooth

Resource
Router
Link
Interface

Change of Paradigms:

Computation Communication

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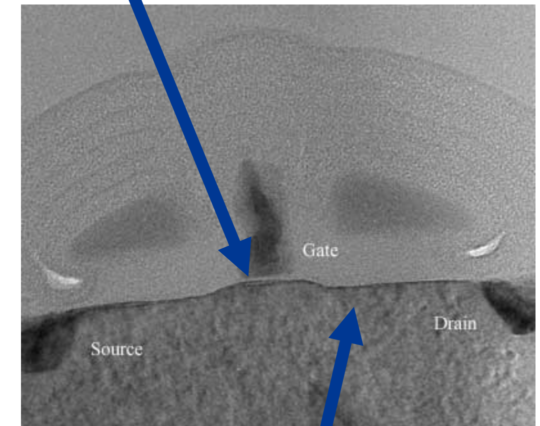
Technology issues

Technology scenario 2010

- Technology node 45 nm
- Chip size 620 mm²
- Transistor count 4424 Mio.
- Physical gate length ~20 nm
- Metal layers 12-16
- Frequency (global-local) 2-12 GHz
- Total wire length ~2.2 km/cm²
  - For M1-M6, 33% usage

[ITRS, 2003 and 2005]

<10 Ångström gate oxide thickness



[Intel, 2001]

<100 dopant atoms

- Approximate size of a resource
  - Rent's rule
  - Reachable die area with clock signal
  - Acceptable power trade-off

~85 resources

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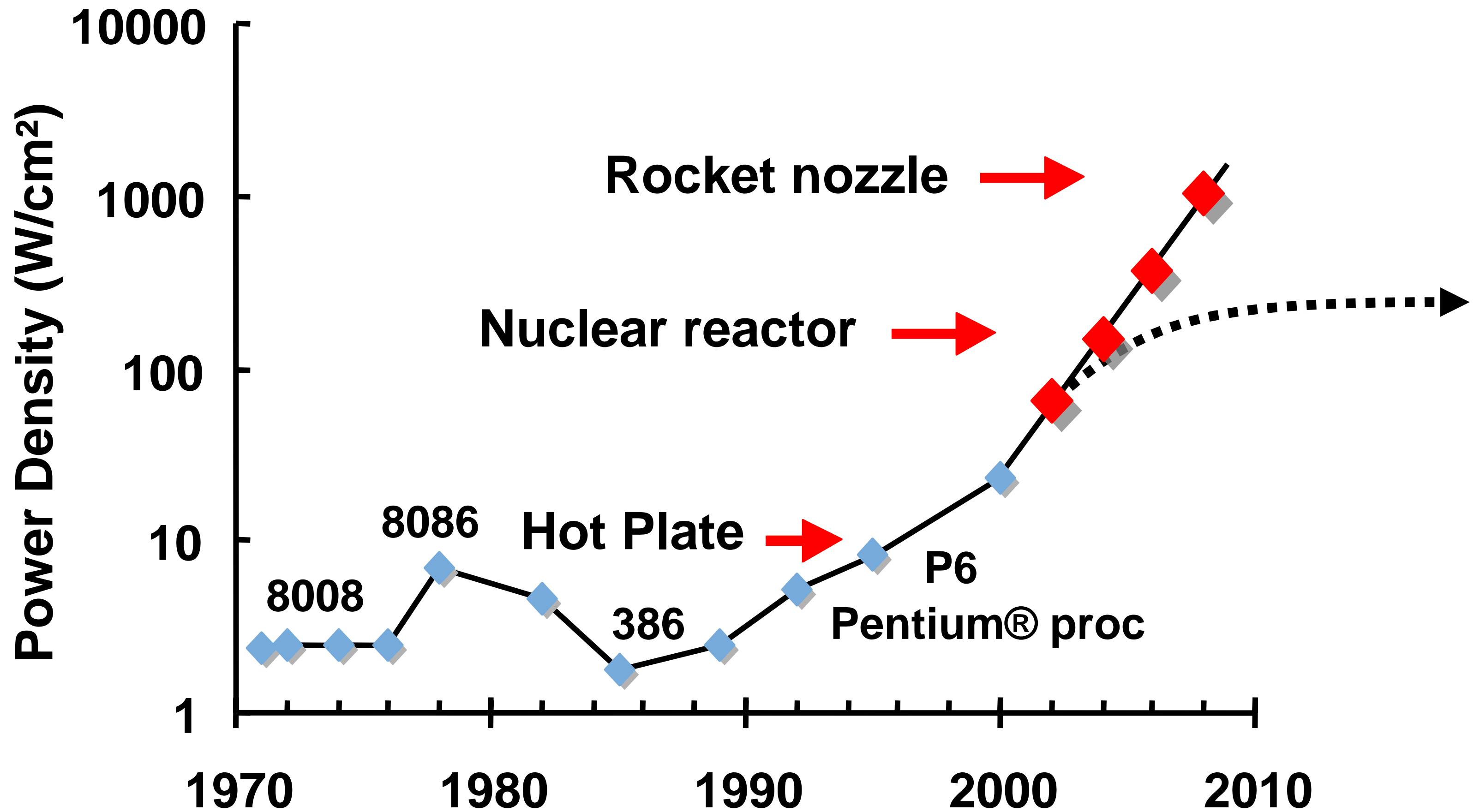
Technology issues

Power density



[Borkar]

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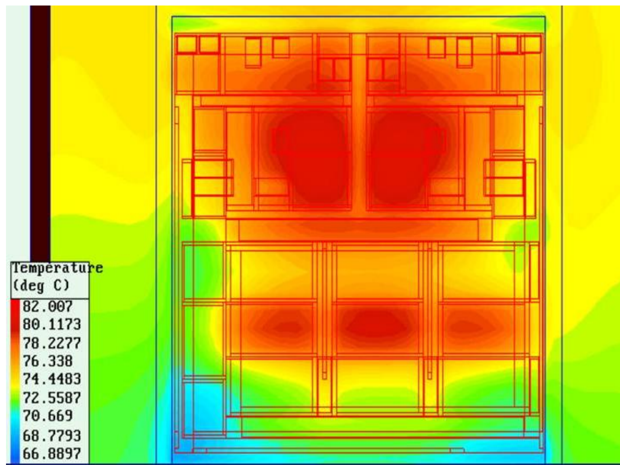
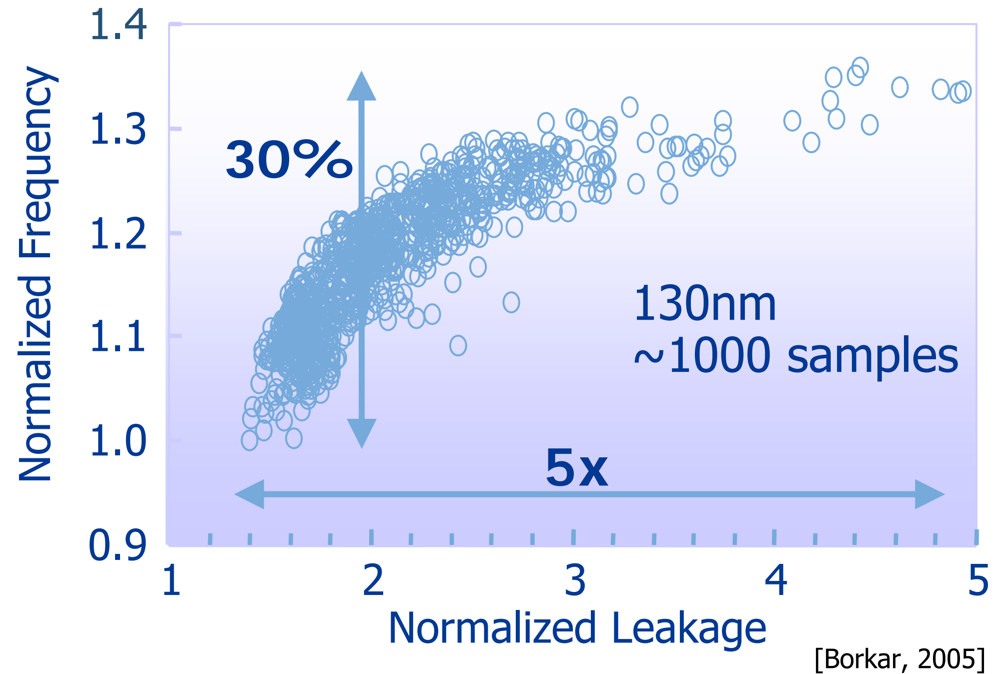
Technology issues

Parameter variability



Power4 Server Chip

[Devgan, 2003]



[Borkar, 2005]

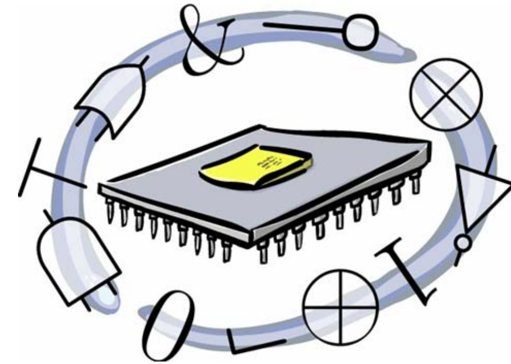
L (nm)	250	180	130	90	65	45
Vt (mV)	450	400	330	300	280	200
σ-Vt (mV)	21	23	27	28	30	32
σ-Vt/Vt	4.7%	5.8%	8.2%	9.3%	10.7%	16%

[ITRS, 2003]

Parameter variability dramatically increasing

Approach

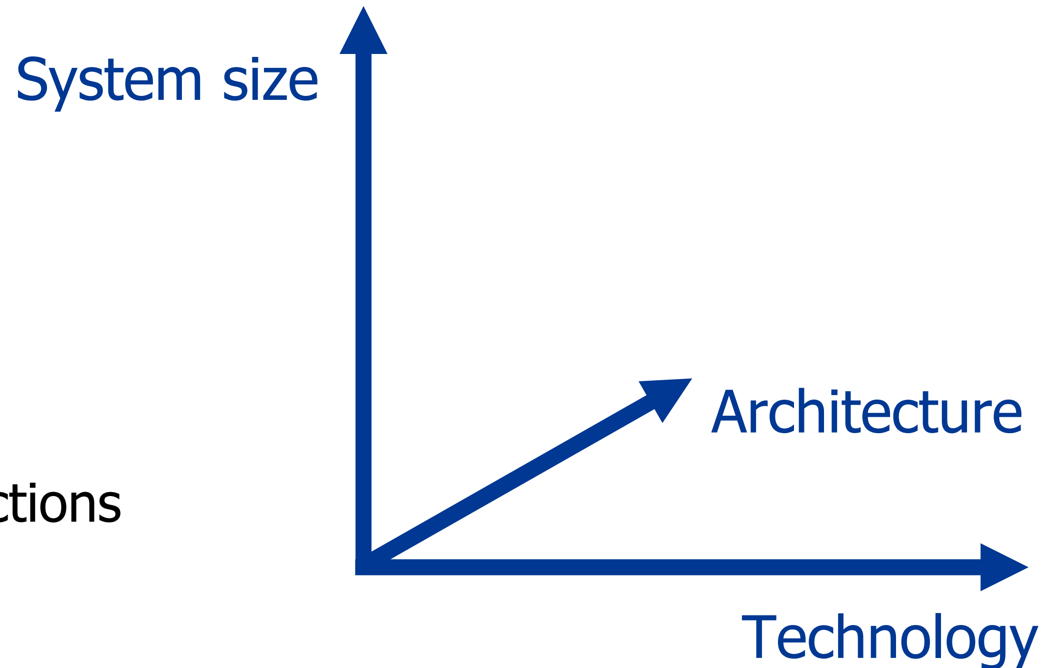
Related work



- Prototyping, Test-Chips
  - Star topology for multimedia applications [Lee, 2003]
  - 4x4 mesh network with traffic generators [Mullins, 2006]
- Parametrizable VHDL-model ported to FPGA [Zeferino, 2004]
- Emulation framework on an FPGA [Genko, 2005]
- High-level VHDL [Sigüenza, 2002]
- SystemC approach and design flow [Jalabert, 2004]
- Event-based C++ Simulator [Wiklund, 2004]

Approach

Design space exploration



1) Analytical models
   - Fast evaluation
   - Inaccurate Predictions

2) Simulation
   - Computation and time intensive
   - Accurate results

Analytical models

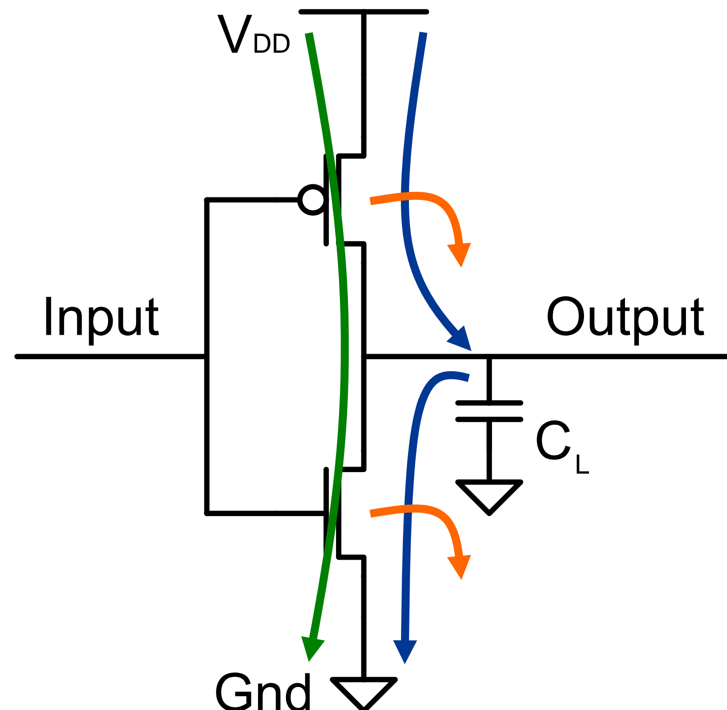
Power equation

$$P_{total} = \alpha C_L V_{DD}^2 f + t_{SC} V_{DD} I_{peak} f + V_{DD} I_{leakage}$$

Dynamic + Short-Circuit + Leakage

E.g. Inverter

Output = $\overline{\text{Input}}$



- Glitches, Spikes, Hazards:
  - Due to race conditions of signals
  - Hard to predict
  - Mostly empirical assessment
- Static power due to design style

Analytical models

Reliability

Process

Random
Systematic
Parametric

Within-die
Die-to-die
Wafer-to-Wafer

Time

Device degradation
Electromigration
Mechanical stress
Thermal stress

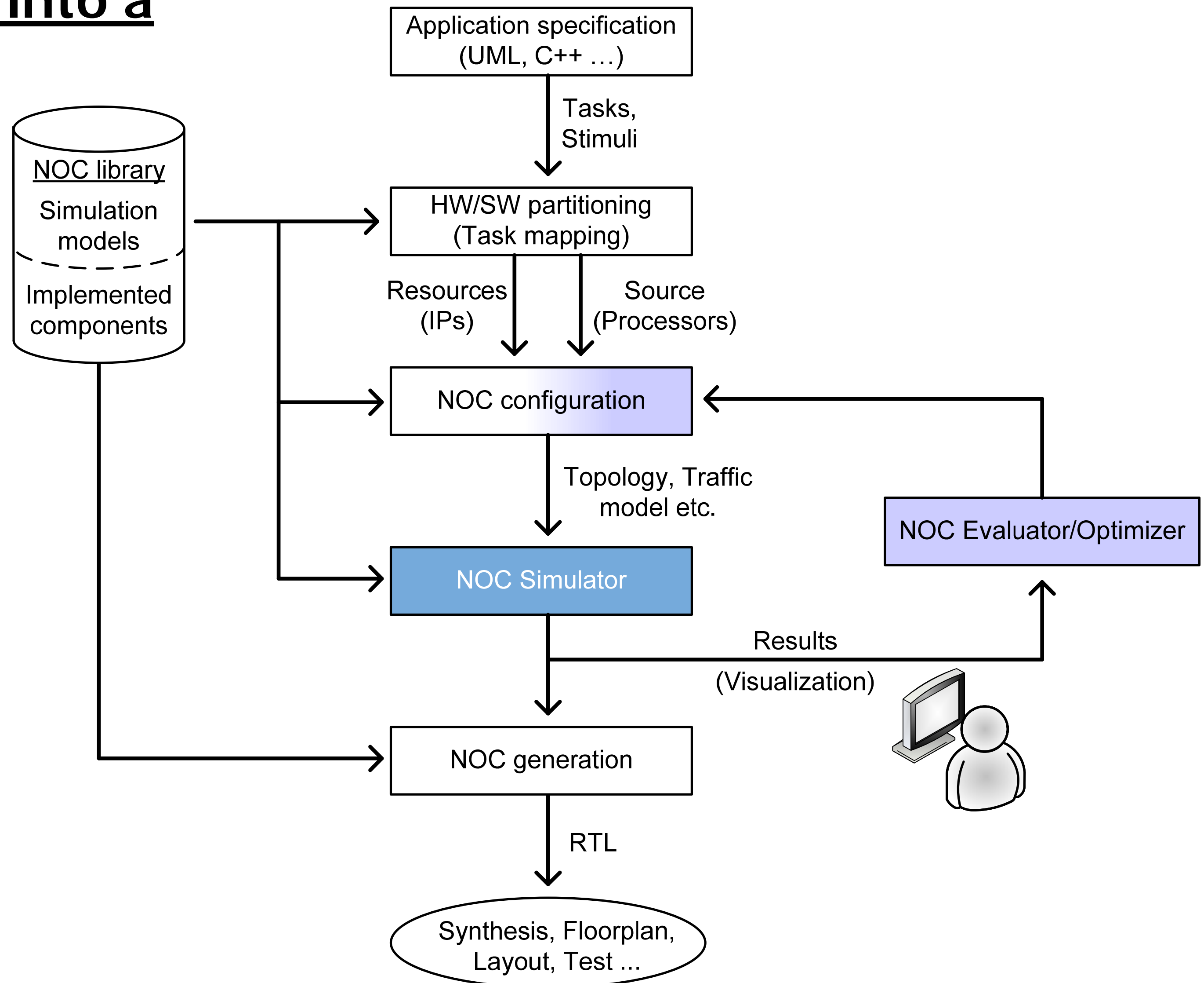
Crosstalk
EMI
α-particles

Power supply
Ambient Temperature
Cooling

Environment

Simulator

Integration into a design flow



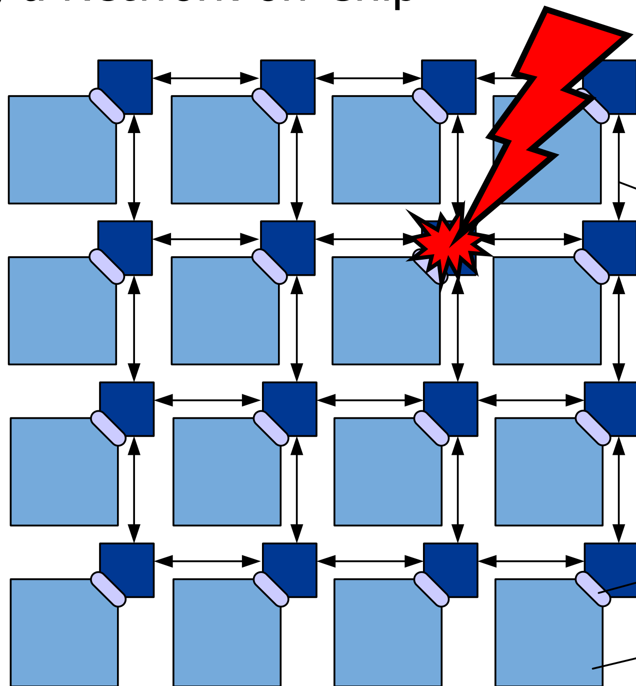
Results

Scenario

Simple example of 16 resources/IPs in a regular 4x4 mesh interconnected with

a) a Network-on-Chip

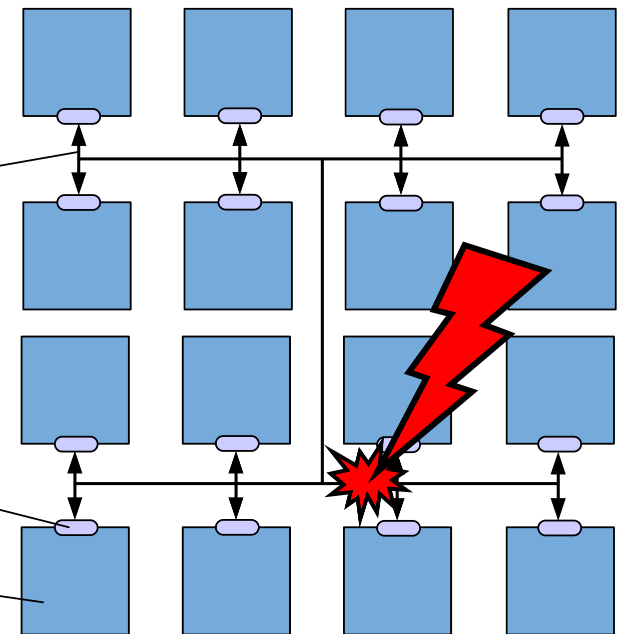
b) a single shared Bus



Link/Inter-connect

Interface

Resource



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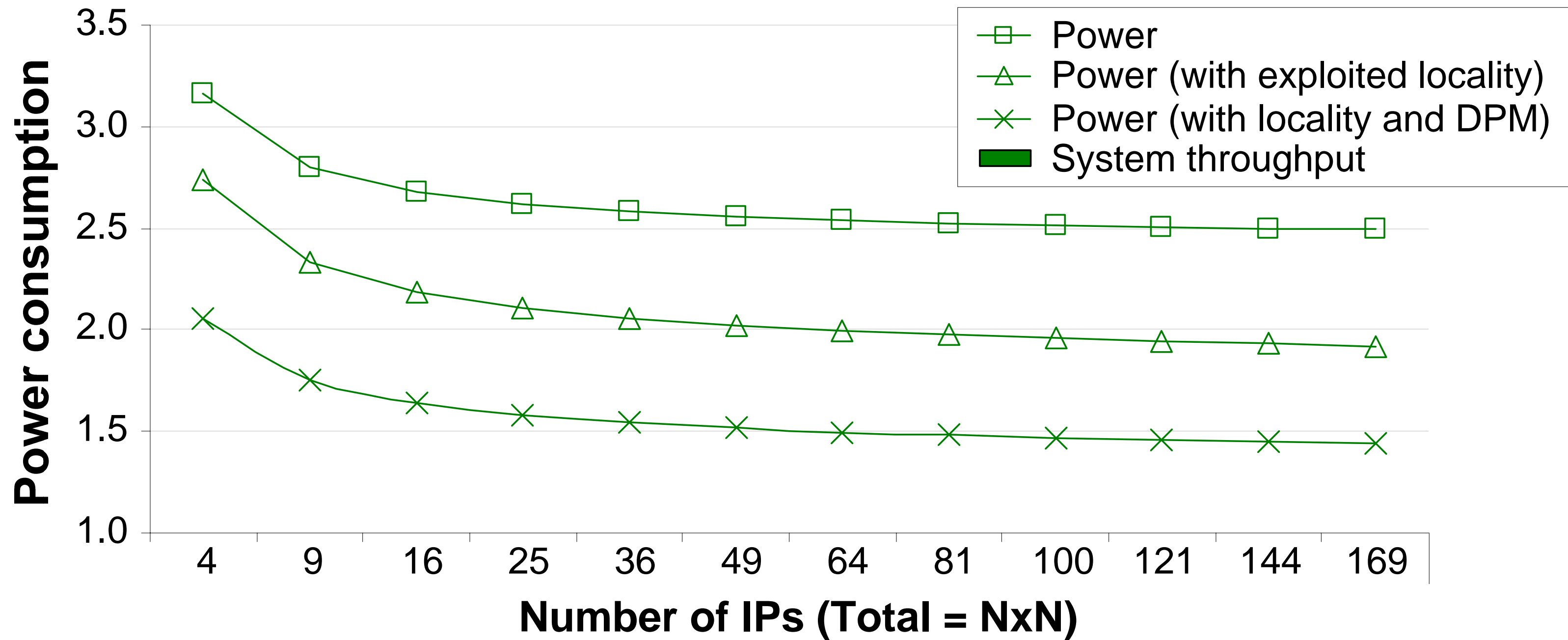
Results

Power and throughput



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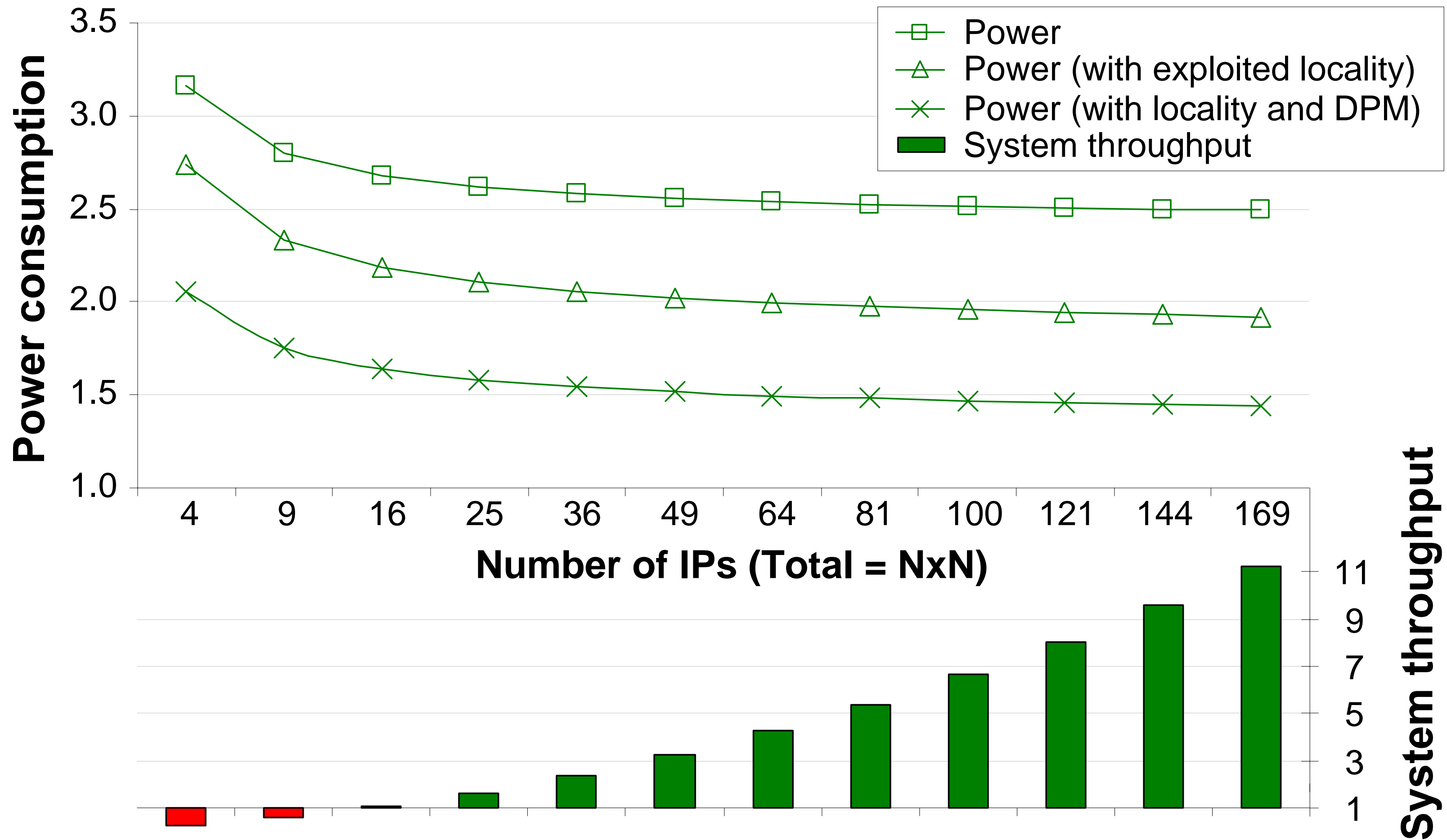
Results

Power and throughput



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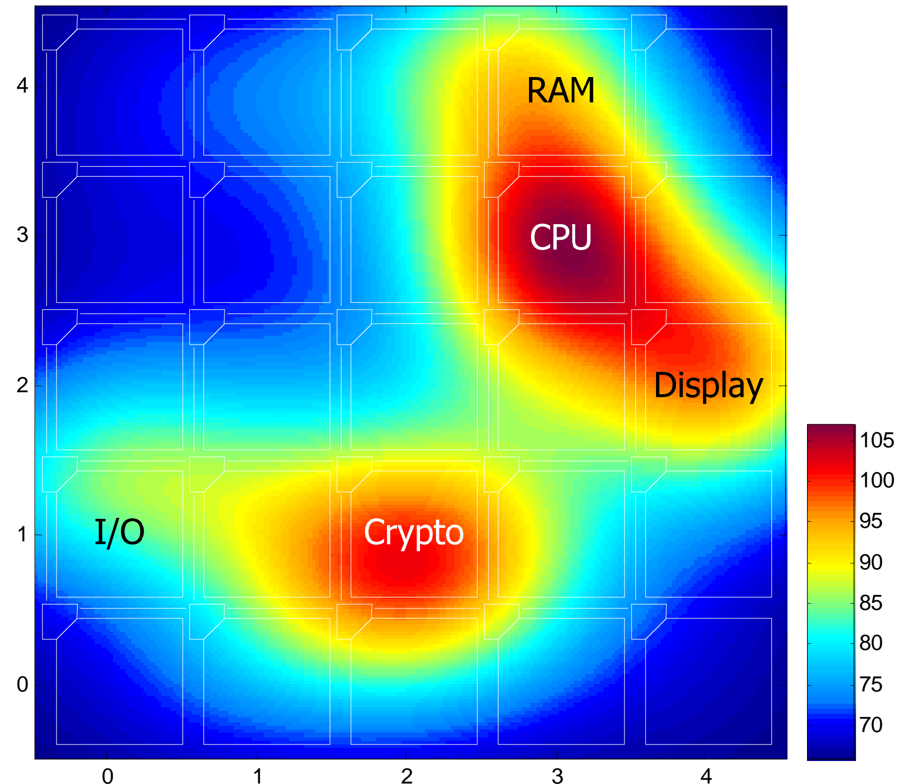
System control

Results

- Temperatur distribution influences
  - ➔ Performance
  - ➔ Power consumption
  - ➔ Reliability
- Dynamic power management
  - ➔ Avoid hot spots
  - ➔ Task mapping
  - ➔ Packet congestions
  - ➔ DV/FS, Clock-gating …



Application example for the temperature distribution of a 5x5 network

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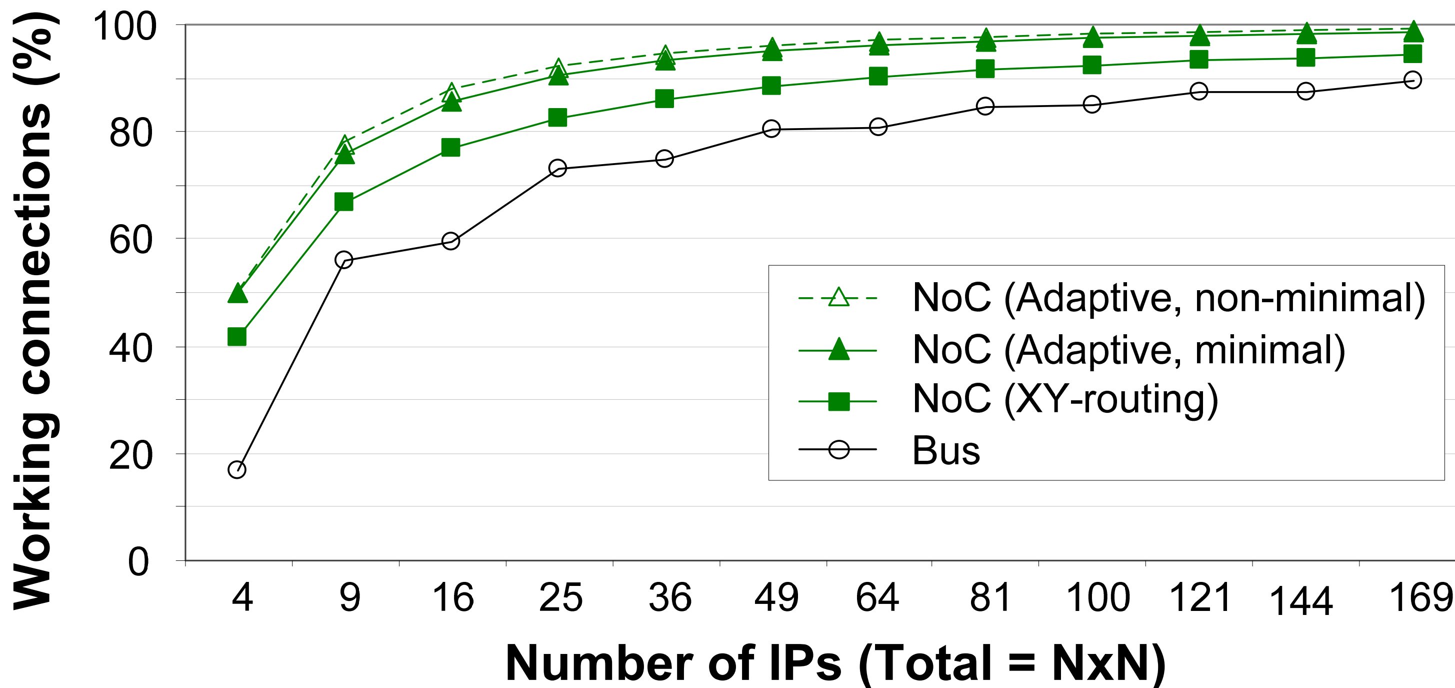
Results

Reliability



- Permanent, single error
- Average number of working connections
- Cohesive connected system

Summary

- Motivation for investigating
  - Networks-on-Chip
  - Power and reliability
- Combined approach for design space exploration
- Comparison of results to a reference bus
- Consideration of dynamic behavior and control